



Huajing Discrete Devices



Silicon N-Channel Power MOSFET

CS540B8

## N-Channel MOSFET



Lead Free Package and Finish

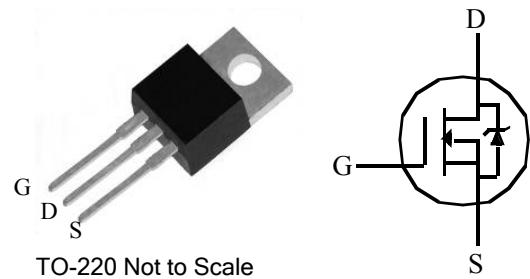
### Applications:

- Automotive
- DC Motor Control
- Class D Amplifier

V <sub>DSS</sub>	R <sub>D(on)</sub> (Max)	I <sub>D</sub>
100V	48mΩ	33A

### Features:

- RoHS Compliant
- Low ON Resistance
- Low Gate Charge
- Peak Current vs Pulse Width Curve
- Inductive Switching Curves



### Ordering Information

PART NUMBER	PACKAGE	BRAND
CS540B8	TO-220	CS540B8

## Absolute Maximum Ratings T<sub>c</sub> = 25 °C unless otherwise specified

Symbol	Parameter	Maximum	Units
V <sub>DSS</sub>	Drain-to-Source Voltage (NOTE *1)	100	V
I <sub>D</sub>	Continuous Drain Current	33	A
I <sub>D@ 100 °C</sub>	Continuous Drain Current	Figure 3	
I <sub>DM</sub>	Pulsed Drain Current, V <sub>GS</sub> @ 10V (NOTE *2)	110	
P <sub>D</sub>	Power Dissipation	128	W
	Derating Factor above 25 °C	0.86	W/ °C
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy L=1.3 mH, ID=20 Amps	260	mJ
I <sub>AS</sub>	Pulsed Avalanche Rating	Figure 8	A
dV/dt	Peak Diode Recovery dV/dt (NOTE *3)	3.0	V/ns
T <sub>L</sub> T <sub>PKG</sub>	Maximum Temperature for Soldering Leads at 0.063in(1.6mm) from Case for 10 seconds Package Body for 10 seconds	300 260	°C
T <sub>J</sub> and T <sub>STG</sub>	Operation Junction and Storage Temperature Range	-55 to 175	°C

\*Drain Current limited by Maximum Junction Temperature

**Caution:** Stresses greater than those listed in "Absolute Maximum Ratings" Table may cause permanent damage to the device.

## Thermal Resistance

Symbol	Parameter	Maximum	Units	Test Condition
R <sub>θJC</sub>	Junction-to-Case	1.17	°C/W	Water cooled heat sink, P <sub>D</sub> adjusted for a peak junction temperature of +175°C .
R <sub>θJA</sub>	Junction-to-Ambient	62	°C/W	1 cubic foot chamber, free air.

**Electrical Characteristics** (  $T_J = 25^\circ\text{C}$  unless otherwise specified):

<b>OFF Characteristics</b>						
Symbol	Parameter	Rating			Units	Test Conditions
		Min.	Typ.	Max.		
$V_{DSS}$	Drain-to-Source Breakdown Voltage	100	--	--	V	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	--	0.71	--	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D=250\mu\text{A}$
$I_{DSS}$	Drain-to-Source Leakage Current	--	--	25	uA	$V_{DS} = 100\text{V}, V_{GS}= 0\text{V},$ $T_a = 25^\circ\text{C}$
		--	--	250		$V_{DS} = 80\text{V}, V_{GS}= 0\text{V},$ $T_a = 125^\circ\text{C}$
$I_{GSS(F)}$	Gate-to-Source Forward Leakage	--	--	+100	nA	$V_{GS} = +20\text{V}$
$I_{GSS(R)}$	Gate-to-Source Reverse Leakage	--	--	-100		$V_{GS} = -20\text{V}$

<b>ON Characteristics</b>						
Symbol	Parameter	Rating			Units	Test Conditions
		Min.	Typ.	Max.		
$R_{DS(ON)}$	Drain-to-Source On-Resistance	--	43	48	m $\Omega$	$V_{GS}=10\text{V}, I_D=16\text{A}$ (NOTE*4)
$V_{GS(TH)}$	Gate Threshold Voltage	2.0	--	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
$g_{fs}$	Forward Transconductance	--	21	--	S	$V_{DS}=30\text{V}, I_D = 16\text{A}$ (NOTE*4)

<b>Dynamic Characteristics</b>						
Symbol	Parameter	Rating			Units	Test Conditions
		Min.	Typ.	Max.		
$C_{iss}$	Input Capacitance	--	1614	--	pF	$V_{GS} = 0\text{V}$ $V_{DS} = 25\text{V}$ $f = 1.0\text{MHz}$ Figure 14
$C_{oss}$	Output Capacitance	--	511	--		
$C_{rss}$	Reverse Transfer Capacitance	--	204	--		
$Q_g$	Total Gate Charge	--	48	--	nC	$V_{DD} = 80\text{V}$ $I_D = 16\text{A}$ $V_{GS} = 10\text{V}$ Figure 15
$Q_{gs}$	Gate-to-Source Charge	--	7.2	--		
$Q_{gd}$	Gate-to-Drain ("Miller")Charge	--	23	--		

<b>Resistive Switching Characteristics</b>						
Symbol	Parameter	Rating			Units	Test Conditions
		Min.	Typ.	Max.		
$t_{d(ON)}$	Turn-on Delay Time	--	13	--	ns	$V_{DD} = 50\text{V}$ $I_D = 16\text{A}$ $V_{GS} = 10\text{V}$ $R_G = 5.1\Omega$
$t_{rise}$	Rise Time	--	30	--		
$t_{d(OFF)}$	Turn-Off Delay Time	--	50	--		
$t_{fall}$	Fall Time	--	25	--		

Source-Drain Diode Characteristics						
Symbol	Parameter	Rating			Units	Test Conditions
		Min.	Typ.	Max.		
I <sub>S</sub>	Continuous Source Current (Body Diode)	--	--	33	A	Integral pn-diode in MOSFET
I <sub>SM</sub>	Maximum Pulsed Current (Body Diode)	--	--	110	A	
V <sub>SD</sub>	Diode Forward Voltage	--	--	1.5	V	I <sub>S</sub> =16A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	--	145	175	ns	V <sub>GS</sub> =0V I <sub>F</sub> =16A, di/dt=100A/us
Q <sub>rr</sub>	Reverse Recovery Charge	--	624	745	nC	

## Notes:

---

- \*1. T<sub>J</sub>=+25°C to +175°C.
  - \*2. Repetitive rating; pulse width limited by maximum junction temperature.
  - \*3. I<sub>SD</sub>=16A di/dt≤100A/us, V<sub>DD</sub>≤BVDSS, T<sub>J</sub>=+175°C.
  - \*4. Pulse width≤380us; duty cycle≤2%.
- 
-

## Characteristics Curve:

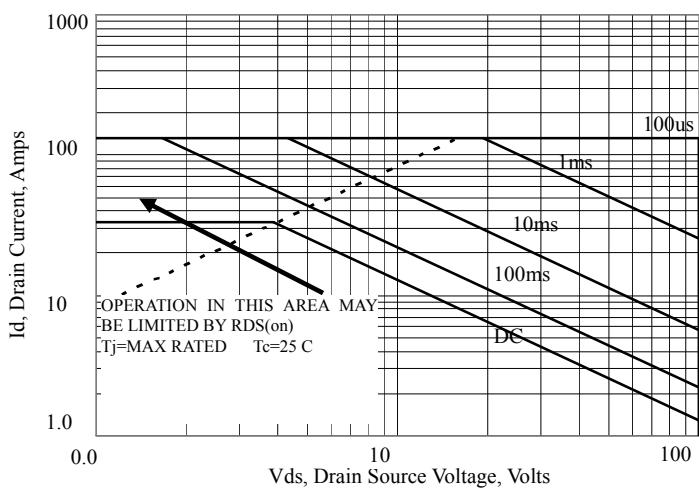


Figure 1 Maximum Forward Bias Safe Operating Area

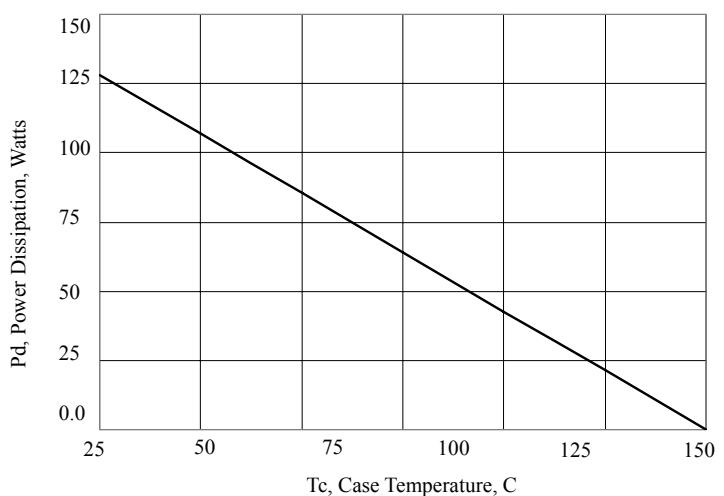


Figure 2 Maximum Power Dissipation vs Case Temperature

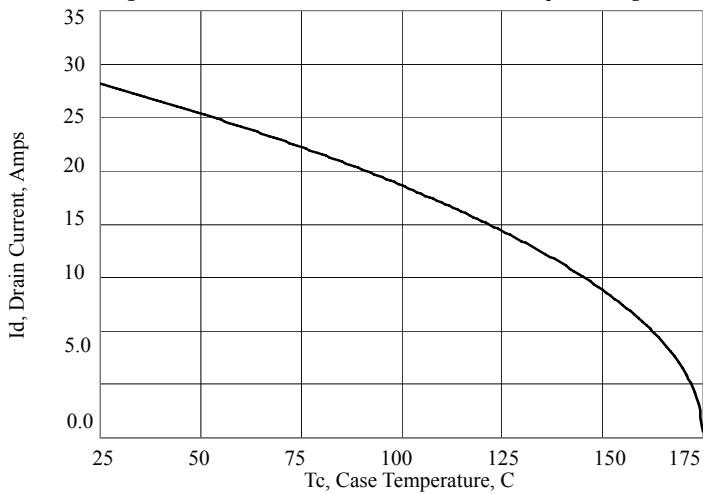


Figure 3 Maximum Continuous Drain Current vs Case Temperature

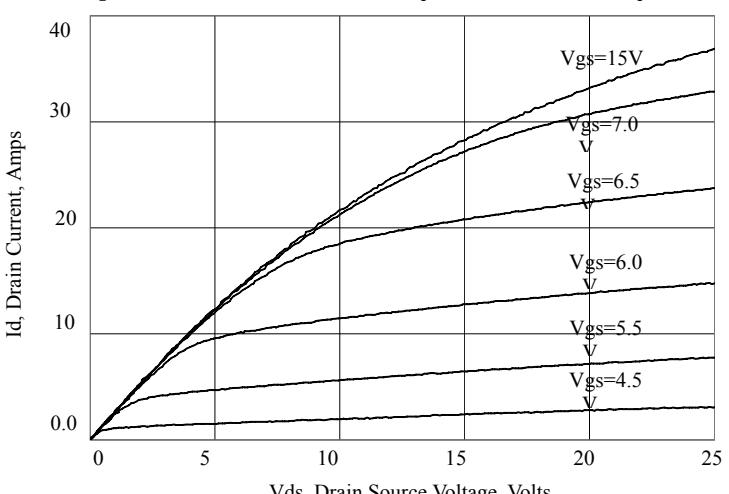


Figure 4 Typical Output Characteristics

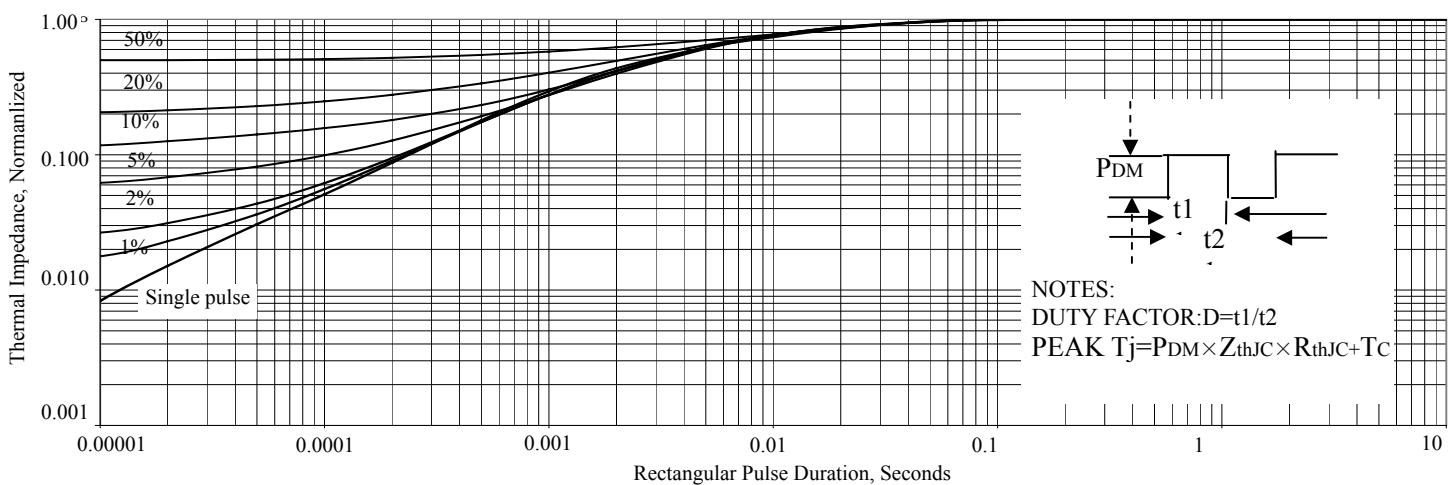


Figure 5 Maximum Effective Thermal Impedance, Junction to case

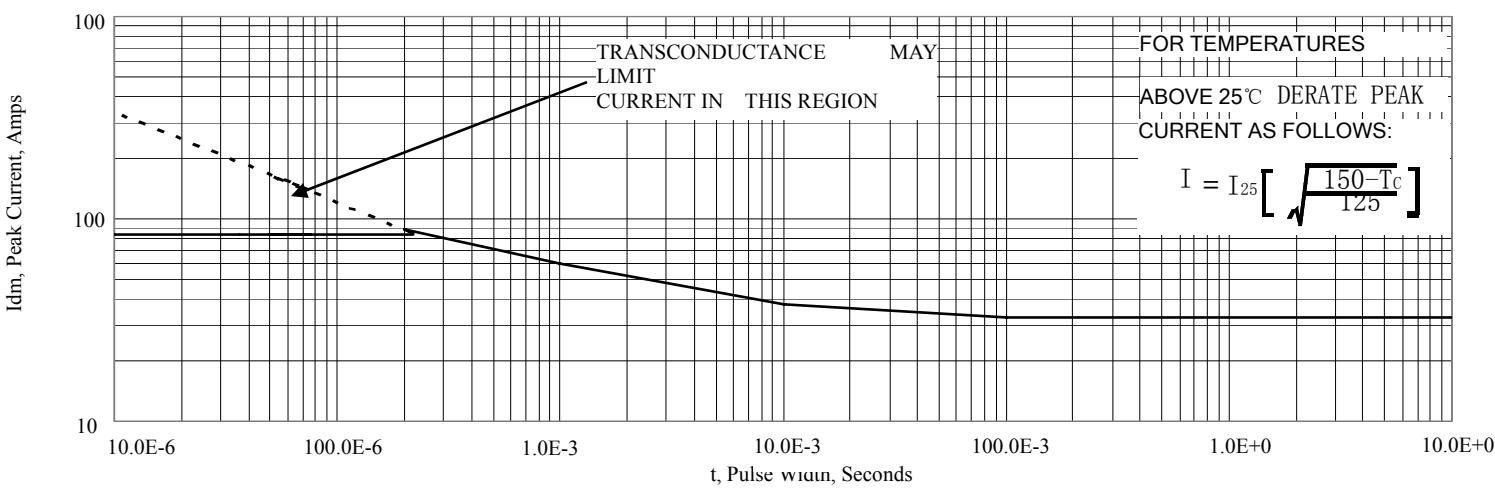


Figure 6 Maximum Peak Current Capability

### Test Circuit and Waveform:

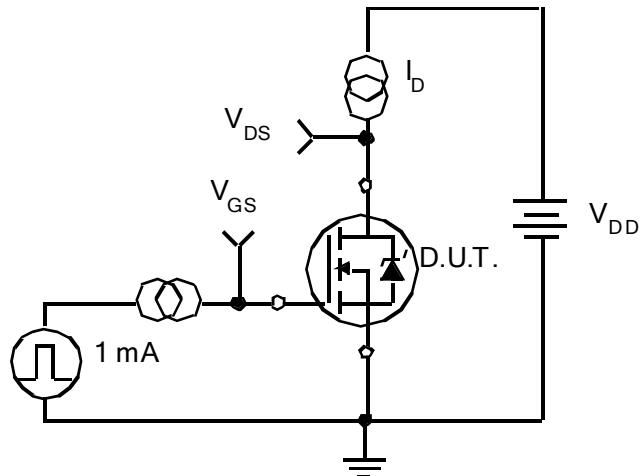


Figure 7 Gate Charge Test Circuit

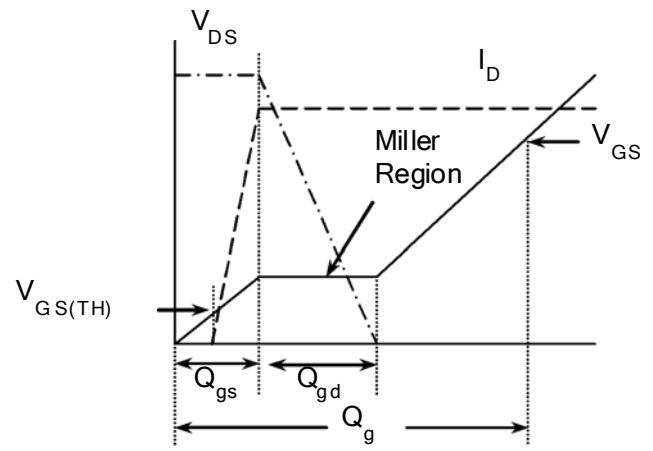


Figure 8 Gate Charge Waveform

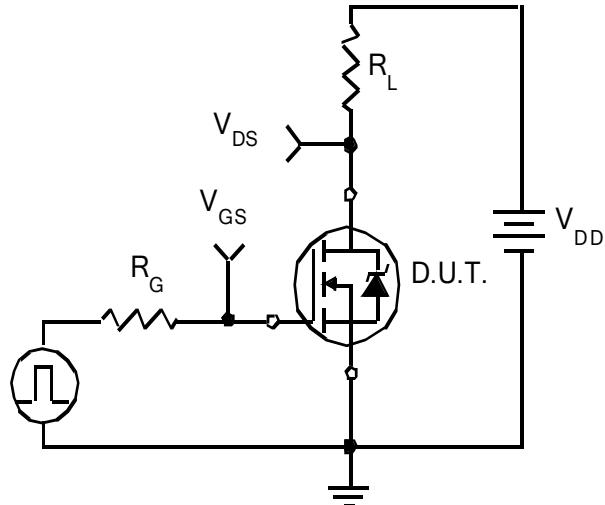


Figure 9 Resistive Switching Test Circuit

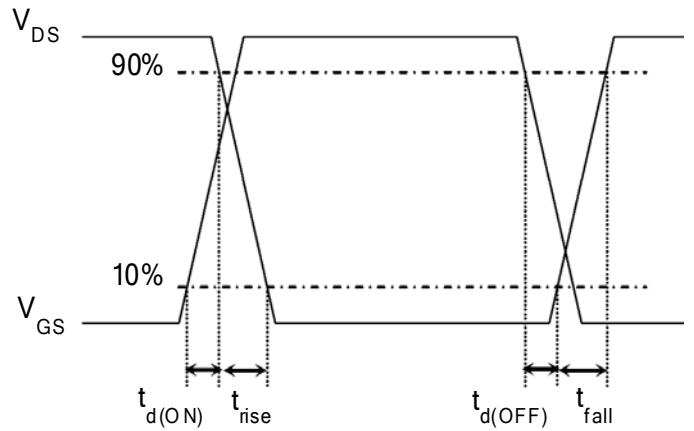
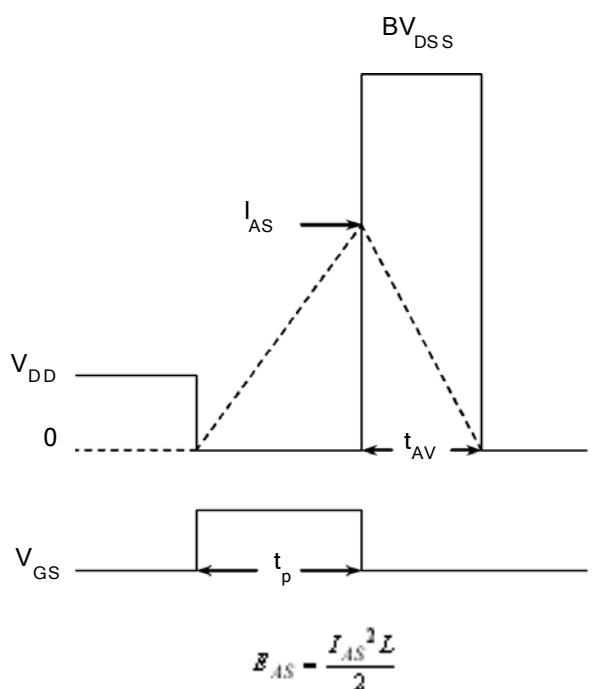
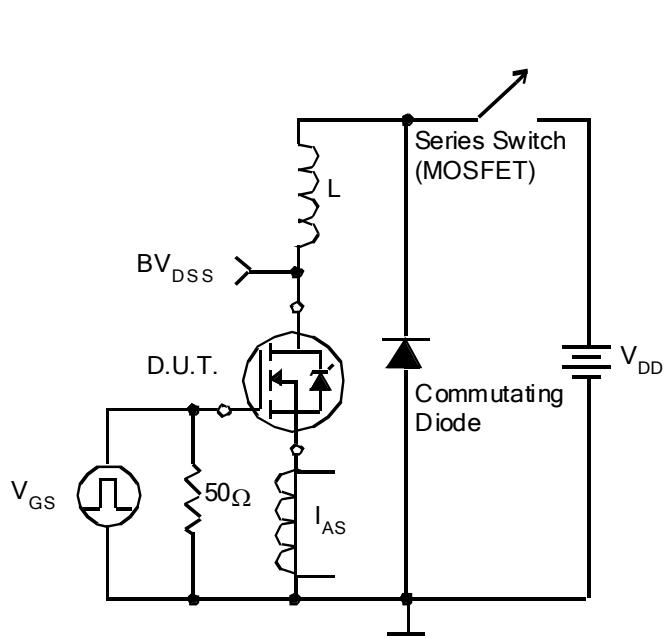
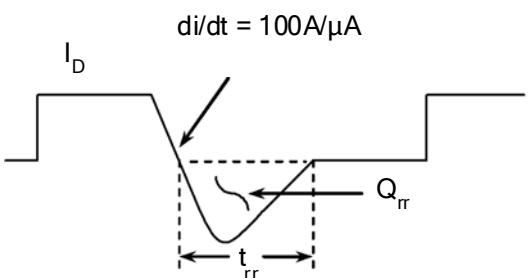
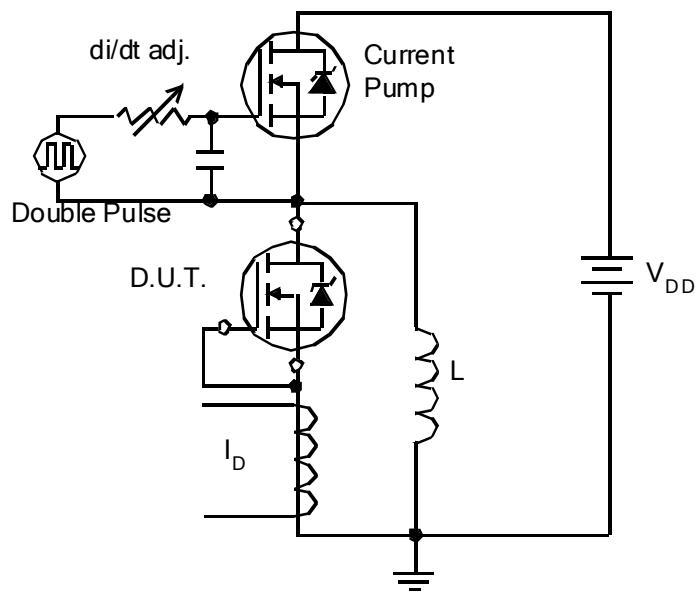
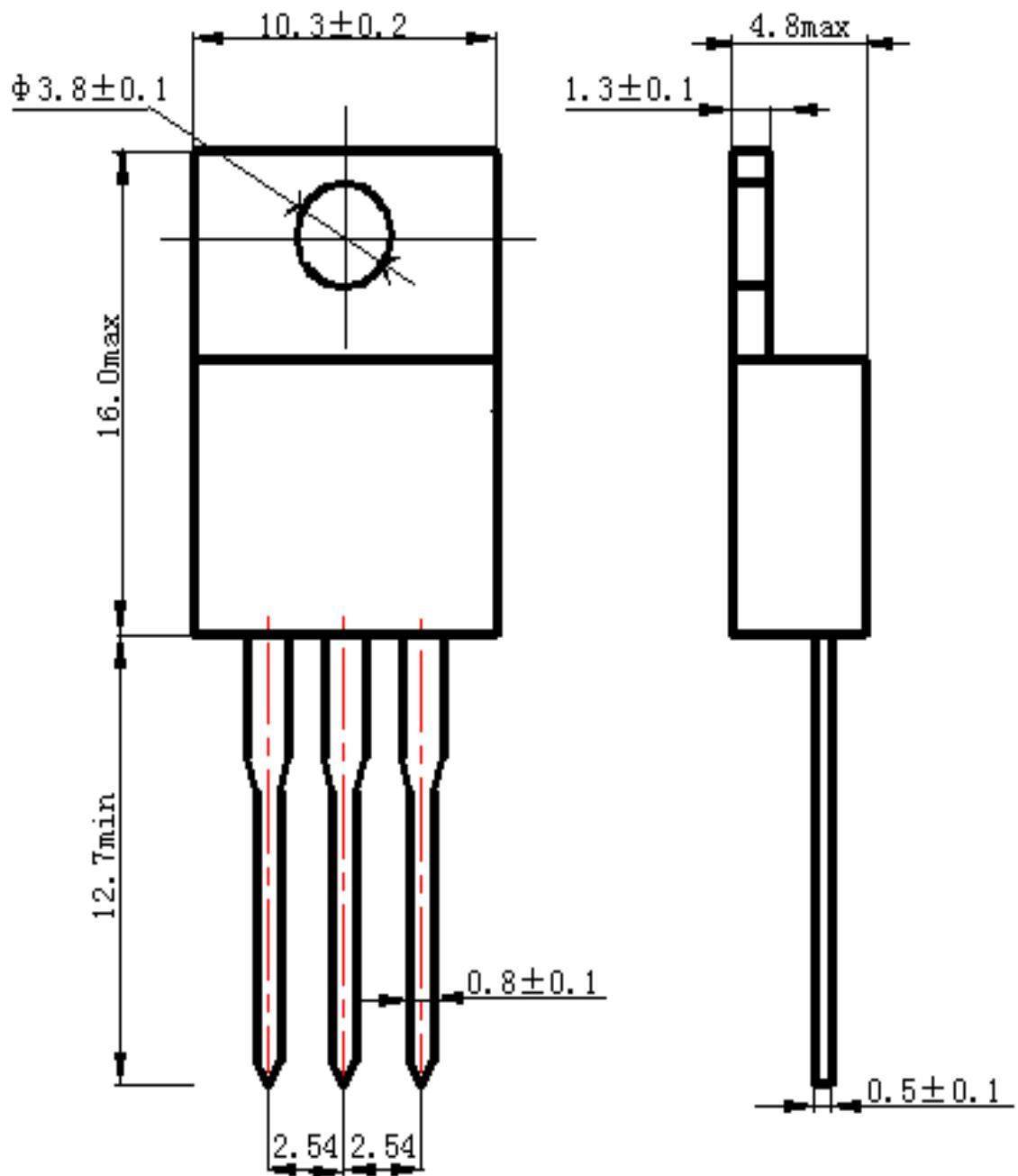


Figure 10 Resistive Switching Waveform

### Test Circuit and Waveform:



**Package Information:**



Unit: mm

TO-220 Package

Part's Name	Hazardous Substance					
	Pb	Hg	Cd	Cr(VI)	PBB	PBDE
<b>Limit</b>	<0.1%	<0.1%	<0.01%	<0.1%	<0.1%	<0.1%
<b>Lead Frame</b>	○	○	○	○	○	○
<b>Molding Compound</b>	○	○	○	○	○	○
<b>Chip</b>	○	○	○	○	○	○
<b>Wire Bonding</b>	○	○	○	○	○	○
<b>Solder</b>	×	○	○	○	○	○
<b>Note</b>	○: Means the hazardous material is under the criterion of SJ/T11363-2006. ×: Means the hazardous material exceeds the criterion of SJ/T11363-2006. The plumbum element of solder exist in products presently, but within the allowed range of Eurogroup's RoHS.					

## Warnings

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. It is suggested to be used under 80 percent of the maximum ratings of the device.
2. When installing the heatsink, please pay attention to the torsional moment and the smoothness of the heatsink.
3. VDMOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. This publication is made by Huajing Microelectronics and subject to regular change without notice.

Add: No.14 Liangxi RD. Wuxi, Jiangsu, China      Mail: 214061      <http://www.crhj.com.cn>  
 Tel: 0510-85807228      Fax: 0510-85800864

Marketing Part:      Post: 214061    Tel / Fax: 0510-85807228-3663/5508  
 E-mail: zhaol@crhj.com.cn    0510-85800360 (Fax)

Application and Service: Post: 214061    Tel / Fax: 0510-85807228-3399 / 2227  
 E-mail: [apply@crhj.com.cn](mailto:apply@crhj.com.cn)